

Appl	licatio	n/Control	No.
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10/808,492 Examiner

Devin Hanan

Applicant(s)/Patent under Reexamination

WETTSTEIN ET AL.

Art Unit

3745

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0	RIGINAL		\		CRO	SS REFERENC	E(S)							
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)											
416	203	416	215	241R										
INTERNATION	AL CLASSIFICATION													
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Devin Hanan 12/23/2005 (Assistant Examiner) (Date)				EDWAKU		Total Claims Allowed: 9								
₩c. (Legal Inst	ruments Examiner) (I	ち Date)	SUPERVISORY PATENT EXAMINER O.G. O.G. TECHNOLOGY CENTER 3700 Print Claim(s) Print Fig. (Primary Examiner) (Date) 1 2											

	Claims renumbered in the same order as presented by applicant							□с	PA	□ T.	D.	 ☐ R.1.47					
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2	2			32			62			92			122		152		182
3	3			33			63			93			123		153		183
4	4			34			64			94			124		154		184
6	5			35			65			95			125		155		185
7	6			36			66			96			126		156		186
8	7			37			67			97			127		157		187
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	11			41			71			101			131		161		191
	12			42			72			102			132		162		192
	13			43			73			103			133		163		193
	14			44			74			104			134		164		194
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	30			60			90	L		120			150		180		210